

Session Title:	[Th1E] Dimensional Metrology V
Session Date:	August 8 (Thu.), 2024
Session Time:	11:00-12:30
Session Room:	Room E (114)
Session Chairs	TBA

[Th1E-1] [Invited] 11:00-11:30

An Optical Measuring Method for Three-dimensional Surface Profile Using Hyperspectrometer

Heulbi Ahn and Jonghan Jin (KRISS, Korea)

[Th1E-2] 11:30-11:45

Real-time Hz-level Broadband Spectrometer

Shuangyou Zhang, Toby Bi, and Pascal Del'Haye (Max Planck Inst. for the Science of Light, Germany)

[Th1E-3] 11:45-12:00

Line Spectral Reflectometry for High-speed, Large-area Thickness Measurement

Minchol Lee (Seoul Nat'l Univ., Korea), Jaehyun Park (Korea Inst. of Industrial Tech., Korea), and Jeongmin Kim (Seoul Nat'l Univ., Korea)

[Th1E-4] 12:00-12:15

Quartz Enhanced Photoacoustic Spectroscopy based on Fabry-Perot Laser for Multigas Monitoring in Coal Mines

Chirag Sahu (Nat'l Inst. of Tech. Raipur, India), Gouri Krishnan (Cochin Univ. of Science and Tech., India), and Ramya Selvaraj (Nat'l Inst. of Tech. Raipur, India)

[Th1E-5] 12:15-12:30

Simultaneous Detection of Carbendazim and Pendimethalin Residues Using a Portable Raman Spectrometer

Peng Zhang, Zheng Feng, Liangguang Du, Weifan Pan, Junid Younus, Xiaowei Guo (Univ. of Electronic Science and Tech. of China, China), and Xue Yang (China Nat'l Tobacco Corp., China)